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I WINIS	UNIT									Sheet 1 of 15																

DESC FORM 193 SEP 87

1. SCOPE						
1.1 Scope. This drawing describes deviwith 1.2.1 of MIL-STD-883, "Provisions for non-JAN devices".	ce require the use	ements of MIL	for class B m STD-883 in co	nicrocircu onjunction	its in accord with complia	ance nt
1.2 Part number. The complete part num	ber shall	be as	shown in the	following	example:	
5962-88699 01 		τ	X        ase outline (1.2,2)		X   	
1.2.1 <u>Device type</u> . The device type sha	ll identi	fy the	circuit func	tion as fo	llows:	
Device type Generic number			Circuit	function		
01 HI-516	16-chan	ne1/di	fferential 8-c	channel CM	OS analog mul	tiplexer
1.2.2 <u>Case outlines</u> . The case outlines as follows:	shall be	as de	signated in ap	pendix C	of MIL-M-38510	), and
Outline letter		<u>Ca se</u>	outline			ļ
X D-10 (28-1 3 C-4 (28-te	ead, 1.490 rminal, .4	)" x . 460" x	610" x .232") .460" x .100'	dual-in-	line package chip carrier	package
1.3 Absolute maximum ratings.				•	·	
Voltage between +V <sub>CC</sub> and -V <sub>CC</sub> Voltage between +V <sub>CC</sub> and ground Voltage between -V <sub>CC</sub> and ground Analog input voltage:  +V <sub>S</sub>	= GND or (	ppen):	+V <sub>CC</sub> + 2.0 -V <sub>CC</sub> - 2.0	) V dc ) V dc ) V dc -150°C	pendix C	
STANDARDIZED	SIZE				5962-88699	
MILITARY DRAWING	Α		privolet i Fran		Т	-
DEFENSE ELECTRONICS SUPPLY CENTER DAYTON, OHIO 45444			REVISION LEVEL	-	SHEET 2	

1.4	Recommended	operating	conditions.

Supply voltage ( $^{\pm}V_{CC}$ ) - - - - - - - - - - - - - - - - - - +15 V dc Analog input voltage ( $^{V}S$ ) - - - - - - - - - - - - - - - +  $^{\pm}V_{CC}$  Input logic low voltage range ( $^{V}A_H$ ) - - - - - - - - - 0 V dc to 0.8 V dc Input logic high voltage range ( $^{V}A_H$ ) - - - - - - - - - - - - 2.4 V dc to  $^{\pm}V_{CC}$  Ambient operating temperature range ( $^{T}A$ ) - - - - - - - - - - - - - - - 55 °C to +125 °C

## 2. APPLICABLE DOCUMENTS

2.1 Government specification and standard. Unless otherwise specified, the following specification and standard, of the issue listed in that issue of the Department of Defense Index of Specifications and Standards specified in the solicitation, form a part of this drawing to the extent specified herein.

SPECIFICATION

MILITARY

MIL-M-38510

- Microcircuits, General Specification for.

STANDARD

MILITARY

MIL-STD-883

- Test Methods and Procedures for Microelectronics.

(Copies of the specification and standard required by manufacturers in connection with specific acquisition functions should be obtained from the contracting activity or as directed by the contracting activity.)

2.2 Order of precedence. In the event of a conflict between the text of this drawing and the references cited herein, the text of this drawing shall take precedence.

#### 3 DECHIDEMENTS

- 3.1 Item requirements. The individual item requirements shall be in accordance with 1.2.1 of MIL-STD-883, "Provisions for the use of MIL-STD-883 in conjunction with compliant non-JAN devices" and as specified herein.
- $3.2\,$  Design, construction, and physical dimensions. The design, construction, and physical dimensions shall be as specified in MIL-M-38510 and herein.
  - 3.2.1 Terminal connections. The terminal connections shall be as specified on figure 1.
  - 3.2.2 Truth table. The truth table shall be as specified on figure 2.
  - 3.2.3 Functional diagram. The functional diagram shall be as specified on figure 3.
  - 3.2.4 Case outlines. The case outlines shall be in accordance with 1.2.2 herein.
- 3.3 Electrical performance characteristics. Unless otherwise specified, the electrical performance characteristics are as specified in table I and apply over the full ambient operating temperature range.
- 3.4 Marking. Marking shall be in accordance with MIL-STD-883 (see 3.1 herein). The part shall be marked with the part number listed in 1.2 herein. In addition, the manufacturer's part number may also be marked as listed in 6.4 herein.

STANDARDIZED MILITARY DRAWING	SIZE A		5962-88699
DEFENSE ELECTRONICS SUPPLY CENTER DAYTON, OHIO 45444		REVISION LEVEL	SHEET 3

	TABLE I.	Electrical performance characte	ristics.			
Test	   Symbol		Group A		mits	Unit
	<u> </u>	-55 C < 1A < +125 C 1/	subgroups	Min	Max	<u> </u>
Input leakage current	IIH	Measure inputs sequentially,  All unused inputs = GND	1, 2, 3	-1.0	1.0	   μΑ 
	IIIL	Measure inputs sequentially,   All unused inputs = +5.0 V	1, 2, 3	-25	   25 	   μ <b>A</b> 
Leakage current into the source terminal of an "OFF" switch	+IS(OFF)	$ V_S  = +10 \text{ V}, V_D = -10 \text{ V},$ $ V_E  = 0.8 \text{ V},$ All unused inputs = -10 V	1, 2, 3	- 50	+50	nA
	-Is(OFF)	$ V_S  = -10 \text{ V}, V_D  = +10 \text{ V},$ $ V_E _N = 0.8 \text{ V},$ $ A  _N = +10 \text{ V}$	1, 2, 3	-50	+50	nΑ
Leakage current into the drain terminal of an "OFF" switch	+ ID(OFF)   	$ V_D  = +10 \text{ V}, V_{EN} = 0.8 \text{ V}, \\  V_S  = -10 \text{ V}, \\  A 1 \text{ unused inputs} = -10 \text{ V}$	1, 2, 3	-100	+100	nA
	-I <sub>D</sub> (OFF)		1, 2, 3	-100	+100	nA
Leakage current from an "ON" driver into the switch (drain)	+ID(ON)	Vs = Vp = +10 V,  All unused inputs = -10 V	1, 2, 3	-100	+100	nΑ
	-I <sub>D</sub> (ON)	  V <sub>S</sub> = V <sub>D</sub> = -10 V,  All unused inputs = +10 V 	1, 2, 3	-100	+100	nA
Positive supply current	+I <sub>CC</sub>	$ V_S  = 0 V$ , $V_D  = 0$ open, $ V_E _V = 2.4 V$ , sequence all $ V_E _V = 2.4 V$ , sequence all $ V_E _V = 2.4 V$ , sequence all	1, 2, 3		+25	mA

STANDARDIZED MILITARY DRAWING	SIZE A		5962-88699				
DEFENSE ELECTRONICS SUPPLY CENTER DAYTON, OHIO 45444		REVISION LEVEL	SHEET 4				

		Cardibiana	Group A	Lim	its	Unit
Test	Symbol   	Conditions $-55^{\circ}\text{C} \leq \text{T}_{\text{A}} \leq +125^{\circ}\text{C} = \frac{1}{4}$	Isubgroups	Min	Max	01110
Negative supply current	1	$V_S$ = 0 V, $V_D$ = open, $V_{EN}$ = 2.4 V, sequence all address combinations, record highest -I <sub>CC</sub>	1, 2, 3	-25       		mΑ
Standby positive supply current	  +I <sub>SBY</sub>	V <sub>A</sub> = 0.8 V, V <sub>EN</sub> = 0.8 V,  V <sub>S</sub> = 0 V, V <sub>D</sub> = open	1, 2, 3	!	+25	mA
Standby negative supply current	-I <sub>SBY</sub>	 	1, 2, 3	<b>-</b> 25		mA
Switch "ON" resistance	+Ros1	V <sub>S</sub> = +10 V, I <sub>D</sub> = -100 μA	1		750	Ω
	1	1	2, 3		1000	Ω
	-RDS1	V <sub>S</sub> = -10 V, I <sub>D</sub> = +100 μA	1		   750 	Ω
		 	2, 3		1000	l Ω
Logic le <b>v</b> el voltage	V <sub>AL</sub> (TTL)	V <sub>DD</sub> /LLS = GND	1, 2, 3	     	0.8	V
	V <sub>AH</sub> (TTL)		1, 2, 3	2.4	1	V
	V <sub>AL</sub> (CMOS)	V <sub>DD</sub> /LLS = +15 V	1, 2, 3	   	4.5	) ) V
	VAH(CMOS)	-	1, 2, 3	10.5	!	٧

STANDARDIZED MILITARY DRAWING	SIZE A				5962-88699	
DEFENSE ELECTRONICS SUPPLY CENTER DAYTON, OHIO 45444			REVISION LEVEL		SHEET	5

Test	Symbol Symbol	Conditions   -55°C ≤ T <sub>A</sub> ≤ +125°C 1/	Group A	Lin	nits	Unit
	1	-55°C < T <sub>A</sub> < +125°C 1/	subgroups  	Min	mfts   Max   10   25   10   175   17	! !
Address input capacitance	CA	  +V <sub>CC</sub> = -V <sub>CC</sub> = 0 V, f = 1.0 MHz  T <sub>A</sub> = +25°C	4     4   		10	l pF i
Output switch capacitance	COS	See 4.3.1c 	4		25	pF
Input switch capacitance	CIS	 	4		10	l pF
Charge transfer error <u>2</u> /	V <sub>CTE</sub>	V <sub>S</sub> = GND, V <sub>EN</sub> = 0 to 5.0 V,   C <sub>L</sub> = 100 pF, f = 500 kHz   T <sub>A</sub> = +25°C	4		20	mV
Off channel isolation $\underline{2}/$	V <sub>ISO</sub>	T   V <sub>EN</sub> = 0.8 V, R <sub>L</sub> = 1.0 kΩ,   C <sub>L</sub> = 40 pF, V <sub>S</sub> = 3.0 V rms,   f = 500 kHz   T <sub>A</sub> = +25°C	4	-55		dB
Break-before-make time delay	t <sub>d</sub>	$ R_L  = 800\Omega$ , $C_L = 12.5$ pF,   See figure 4	9	10		ns
	   	  -  -	10	2.0		ns
	   		11 2/	2.0		l ns
Propagation delay time, enable to I/O	ton(EN)	]    -	9		175 	l ns
	   	<u> </u> 	10,11		225	l l ns
	toff(EN)	   	j 9 		175	l ns
	1 	 	10, 11		225	ns

STANDARDIZED MILITARY DRAWING	SIZE <b>A</b>		5962-88699
DEFENSE ELECTRONICS SUPPLY CENTER DAYTON, OHIO 45444		REVISION LEVEL	SHEET 6

Test	Symbol	Conditions   -55°C < TA < +125°C 1/	Group A	Li	Limits	
	 	-55°C ≤ TA ≤ +125°C 1/	subgroups	Min	Max	
Propagation delay time, address inputs to I/O	tA	$ R_L  = 10 M\Omega$ , $C_L = 12.5 pF$ , $ See figure 4 $	9		175	ns
channel	 		10, 11		   225 	l I ns
Functional test	i I		7,8		j I	

- $^{1/}$   $^{+}\text{V}_{CC}$  = +15 V,  $^{-}\text{V}_{CC}$  = -15 V,  $\text{V}_{EN}$  = 2.4 V,  $\text{V}_{DD}/\text{LLS}$  = GND,  $\text{V}_{AH}$  = 2.4 V and  $\text{V}_{AL}$  = 0.8 V, unless otherwise specified.
- 2/ Guaranteed, but not tested to the limits specified in table I.
- 3.5 Certificate of compliance. A certificate of compliance shall be required from a manufacturer in order to be listed as an approved source of supply in 6.4. The certificate of compliance submitted to DESC-ECS prior to listing as an approved source of supply shall state that the manufacturer's product meets the requirements of MIL-STD-883 (see 3.1 herein) and the requirements herein.
- 3.6 Certificate of conformance. A certificate of conformance as required in MIL-STD-883 (see 3.1 herein) shall be provided with each lot of microcircuits delivered to this drawing.
- 3.7 Notification of change. Notification of change to DESC-ECS shall be required in accordance with MIL-STD-883 (see 3.1 herein).
- 3.8 Verification and review. DESC, DESC's agent, and the acquiring activity retain the option to review  $\frac{1}{1}$  the manufacturer's facility and applicable required documentation. Offshore documentation shall be made available onshore at the option of the reviewer.

STANDARDIZED MILITARY DRAWING	SIZE A		5962-88699	
DEFENSE ELECTRONICS SUPPLY CENTER DAYTON, OHIO 45444		REVISION LEVEL	SHEET 7	

Device type	01
Case outlines	X and 3
Terminal number	Terminal connection
1 2 3 4 5 6 7 8 9 10 11 12 13 14 15 16 17 18 19 20 21 22 23 24 25 26 27 28	+VCC OUT B No connection IN 16/8B IN 15/7B IN 14/6B IN 13/5B IN 12/4B IN 11/3B IN 10/2B IN 9/1B GND VDD/LLS A3/SDS A2 A1 A0 Enable IN 1/1A IN 2/2A IN 3/3A IN 4/4A IN 5/5A IN 6/6A IN 7/7A IN 8/8A -VCC

FIGURE 1. Terminal connections.

STANDARDIZED
MILITARY DRAWING
DEFENSE ELECTRONICS SUPPLY CENTER
DAYTON, OHIO 45444

SIZE
A
5962-88699

REVISION LEVEL
SHEET
8

16-channel multiplexer operation.  $\underline{1}/\underline{2}/$ 

Use A <sub>3</sub> as digital address input					On chan	nel to
Enable	A <sub>3</sub>	A <sub>2</sub>	A <sub>1</sub>	A <sub>O</sub>	A TUO	OUT B
L L	x [	x	х	х	None	None
   H	L	L	L	L	1A	None
   H	L	L	L	н	2A	None
   H	L I	L	н	L	3A	None
[   H	L	L	н	н	4A	None
[   H	L	H	L	L	5 <b>A</b>	None
   H	L	н	L	н	6A	None
   H	L	н	н	L	7 <b>A</b>	None
   H	L	н	н	н	8A	None
   H	   H	L	L	L	None	1B
   H	l l	L	L	Н	None	28
   H	ļ ļ H	   L	Н	L	None	1   38
!   н	l l H	L	H	н	None	1   4B
l   н	Н	   H	l L	L	None	1   5B
l H	H	l l H	ļ L	l H	l None	l 68
   <b>H</b>	   H	   H	l I H	L	   None	   7B
H H	   H 	   H 	   H 	Н [	   None 	88 

FIGURE 2. <u>Truth table</u>.

STANDARDIZED MILITARY DRAWING	SIZE A		5962	2-88699	
DEFENSE ELECTRONICS SUPPLY CENTER DAYTON, OHIO 45444		REVISION LI	EVEL	SHEET	

DESC FORM 193A SEP 87 Differential 8-channel multiplexer operation.  $\frac{2}{3}$ 

A <sub>3</sub> connected to -V <sub>CC</sub>			On char	nnel to	
Enable	A <sub>2</sub>	A <sub>1</sub>	A <sub>0</sub>	OUT A	OUT B
l L	i x	į x	X	None	None
н	l L	L	L	1A	1B
i H	L	Ĺ	H	2A	2B
I } Н	! ! L	!   H	Ļ	3A	   3B
l H	L	   H	Н	4A	   4B
   H	   H	L	ļ L	5A	5B
   H	†   H	l L	H	6A	l   6B
ļ   Н	Н	Н	ļ Ļ L	7A	   7B
   H	   H	   H	H	8A	   88 

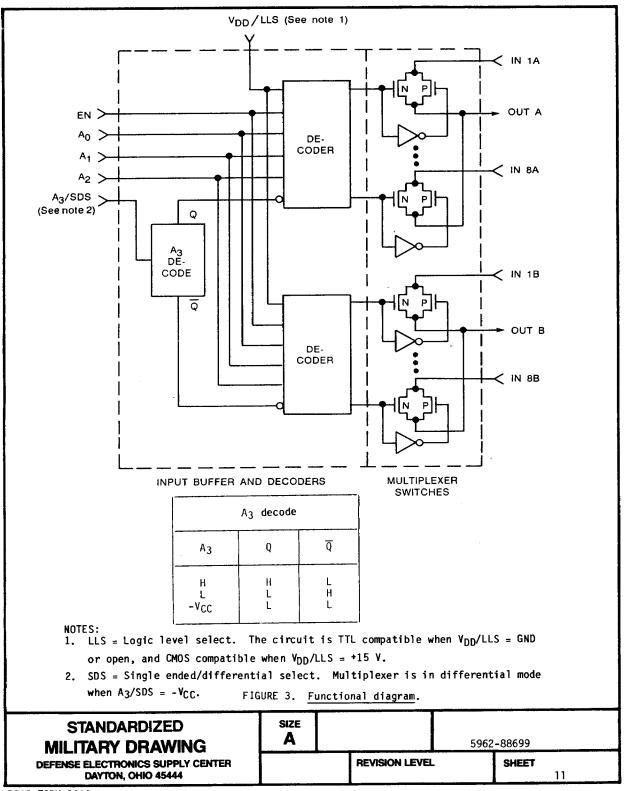
- $1/\ \mbox{For 16-channel operation, connect OUT A to OUT B.}$
- 2/H = High logic level
  - L = Low logic level X = Don't care
- $\frac{3}{4}$  For differential 8-channel operation, use the A<sub>3</sub> address pin to select the differential mode where A<sub>3</sub> = - $^{4}$ CC and OUT A is not connected to

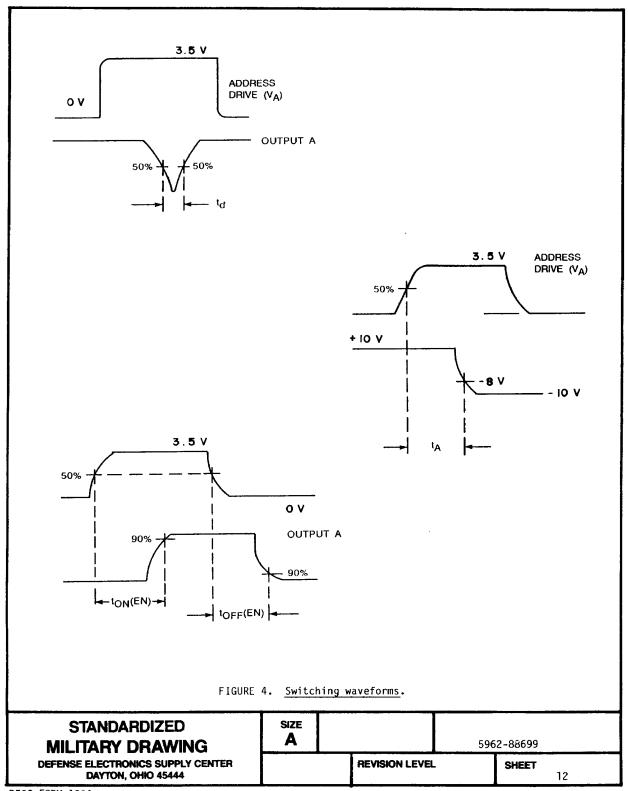
FIGURE 2. Truth table - Continued.

# **STANDARDIZED MILITARY DRAWING**

DEFENSE ELECTRONICS SUPPLY CENTER DAYTON, OHIO 45444

SIZE Α 5962-88699 **REVISION LEVEL** SHEET 10





- 4. QUALITY ASSURANCE PROVISIONS
- 4.1 Sampling and inspection. Sampling and inspection procedures shall be in accordance with section 4 of MIL-M-38510 to the extent specified in MIL-STD-883 (see 3.1 herein).
- 4.2 <u>Screening</u>. Screening shall be in accordance with method 5004 of MIL-STD-883, and shall be conducted on all devices prior to quality conformance inspection. The following additional criteria shall apply:
  - a. Burn-in test, method 1015 of MIL-STD-883.
    - (1) Test condition A, B, C, or D using the circuit submitted with the certificate of compliance (see 3.5 herein).
    - (2)  $T_A = +125^{\circ}C$ , minimum.
  - b. Interim and final electrical test parameters shall be as specified in table II herein, except interim electrical parameter tests prior to burn-in are optional at the discretion of the manufacturer.
- 4.3 Quality conformance inspection. Quality conformance inspection shall be in accordance with method 5005 of MIL-STD-883 including groups A, B, C, and D inspections. The following additional criteria shall apply.
  - 4.3.1 Group A inspection.
    - a. Tests shall be as specified in table II herein.
    - b. Subgroups 5 and 6 in table I, method 5005 of MIL-STD-883 shall be omitted.
    - c. Subgroup 4 (capacitance measurement) shall be measured for inital qualification and after process or design changes which may affect capacitance. Sample size is fifteen devices, all input and output terminals tested, and no failures.
    - d. Subgroups 7 and 8 test sufficient to verify truth table.
  - 4.3.2 Groups C and D inspections.
    - a. End-point electrical parameters shall be as specified in table II herein.
    - b. Steady-state life test conditions, method 1005 of MIL-STD-883.
      - (1) Test condition A, B, C, or D using the circuit submitted with the certificate of compliance (see 3.5 herein).
      - (2)  $T_A = +125^{\circ}C$ , minimum.
      - (3) Test duration: 1,000 hours, except as permitted by method 1005 of MIL-STD-883.

STANDARDIZED MILITARY DRAWING	SIZE A		5962-88699	
DEFENSE ELECTRONICS SUPPLY CENTER DAYTON, OHIO 45444		REVISION LEVEL	SHEET	13

TABLE II. Electrical test requirements.

MIL-STD-883 test requirements	Subgroups   (per method   5005, table I)
Interim electrical parameters (method 5004)	
Final electrical test parameters (method 5004)	1*,2,3,7,8,   9,10,11
Group A test requirements (method 5005)	1,2,3,4**,7,8, 9,10,11
Groups C and D end-point electrical parameters (method 5005)	1

<sup>\*</sup> PDA applies to subgroup 1.

### 5. PACKAGING

5.1 Packaging requirements. The requirements for packaging shall be in accordance with MIL-M-38510.

### 6. NOTES

- 6.1 Intended use. Microcircuits conforming to this drawing are intended for use when military specifications do not exist and qualified military devices that will perform the required function are not available for OEM application. When a military specification exists and the product covered by this drawing has been qualified for listing on QPL-38510, the device specified herein will be inactivated and will not be used for new design. The QPL-38510 product shall be the preferred item for all applications.
- 6.2 Replaceability. Microcircuits covered by this drawing will replace the same generic device covered by a contractor-prepared specification or drawing.
- 6.3 Comments. Comments on this drawing should be directed to DESC-ECS, Dayton, Ohio 45444, or telephone  $513-\overline{2}96-5375$ .

STANDARDIZED
MILITARY DRAWING
DEFENSE ELECTRONICS SUPPLY CENTER
DAYTON, OHIO 45444

SIZE
A
5962-88699

REVISION LEVEL
SHEET
14

<sup>\*\*</sup> See 4.3.1c.

6.4 Approved source of supply. An approved source of supply is listed herein. Additional sources will be added as they become available. The vendor listed herein has agreed to this drawing and a certificate of compliance (see 3.5 herein) has been submitted to DESC-ECS.

Military drawing     part number	Vendor CAGE number	Vendor   similar part   number <u>1</u> /
5962-8869901XX	34371	   HI1-516/883 
5962-88699013X	34371	   HI4-516/883 

 $\frac{1}{I}$  Caution. Do not use this number for item acquisition. Items acquired by this number may not satisfy the performance requirements of this drawing.

Vendor CAGE number

34371

Vendor name and address

Harris Semiconductor P.O. Box 883 Melbourne, FL 32901

STANDARDIZED **MILITARY DRAWING** DEFENSE ELECTRONICS SUPPLY CENTER

DAYTON, OHIO 45444

SIZE Α

REVISION LEVEL

5962-88699

SHEET